PD - 94818

# International Rectifier

## IRF520NPbF

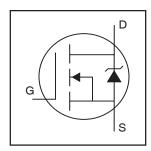
HEXFET® Power MOSFET

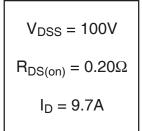
- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

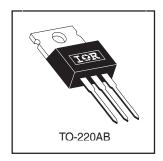
#### Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.







#### **Absolute Maximum Ratings**

Parameter Max.					
	Parameter	IVIAX.	Units		
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V	9.7			
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	6.8	A		
I <sub>DM</sub>	Pulsed Drain Current ①	38			
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	48	W		
	Linear Derating Factor	0.32	W/°C		
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V		
E <sub>AS</sub>	Single Pulse Avalanche Energy®	91	mJ		
I <sub>AR</sub>	Avalanche Current①	5.7	A		
E <sub>AR</sub>	Repetitive Avalanche Energy①	4.8	mJ		
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns		
T <sub>J</sub>	Operating Junction and	-55 to + 175			
T <sub>STG</sub>	Storage Temperature Range		°C		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )			
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)			

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		3.1	
R <sub>θCS</sub>	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.11		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.20	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 5.7A ⊕
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
9fs	Forward Transconductance	2.7			S	$V_{DS} = 50V, I_{D} = 5.7A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			25	μА	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V
צצטי	Brain to Gource Leakage Guiterit			250	μΛ	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
lasa	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	''^	V <sub>GS</sub> = -20V
Qg	Total Gate Charge			25		I <sub>D</sub> = 5.7A
Q <sub>gs</sub>	Gate-to-Source Charge			4.8	nC	$V_{DS} = 80V$
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge			11		$V_{GS}$ = 10V, See Fig. 6 and 13 $\oplus$
t <sub>d(on)</sub>	Turn-On Delay Time		4.5			$V_{DD} = 50V$
t <sub>r</sub>	Rise Time		23		no	$I_D = 5.7A$
t <sub>d(off)</sub>	Turn-Off Delay Time		32		ns	$R_G = 22\Omega$
t <sub>f</sub>	Fall Time		23			$R_D = 8.6\Omega$ , See Fig. 10 $\oplus$
L <sub>D</sub>	Internal Drain Inductance		4.5			Between lead,
D	Internal Drain Inductance 4.5 —		nH	6mm (0.25in.)		
L <sub>S</sub>	Internal Source Inductance		7.5		'''	from package
						and center of die contact
C <sub>iss</sub>	Input Capacitance		330			$V_{GS} = 0V$
Coss	Output Capacitance		92		pF	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		54			f = 1.0MHz, See Fig. 5

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			9.7		MOSFET symbol
	(Body Diode)		9.7	A	showing the	
I <sub>SM</sub>	Pulsed Source Current			-00		integral reverse
	(Body Diode) ①	38	30		p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$ , $I_S = 5.7A$ , $V_{GS} = 0V$ ④
t <sub>rr</sub>	Reverse Recovery Time		99	150	ns	$T_J = 25^{\circ}C, I_F = 5.7A$
Q <sub>rr</sub>	Reverse RecoveryCharge		390	580	nC	di/dt = 100A/µs ⊕

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- $\begin{tabular}{ll} $\mathbb{O}$ $V_{DD}=25V$, starting $T_J=25^{\circ}C$, $L=4.7mH$ \\ $R_G=25\Omega$, $I_{AS}=5.7A$. (See Figure 12) \\ \end{tabular}$
- $\label{eq:loss} \begin{array}{l} \text{ } \\ \text{ }$
- 4 Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$ .

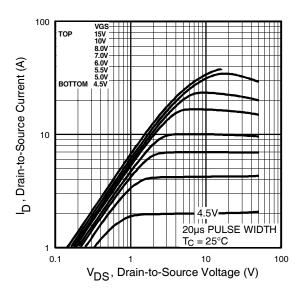
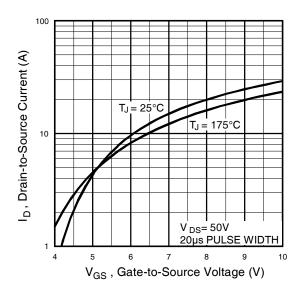


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics



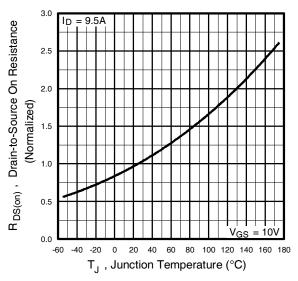
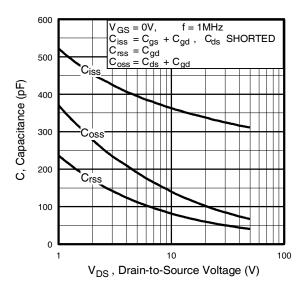
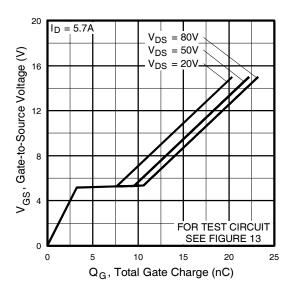


Fig 3. Typical Transfer Characteristics

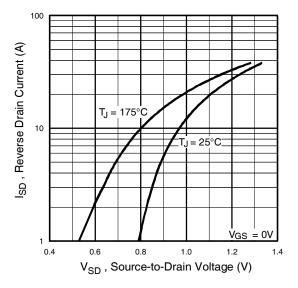
**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

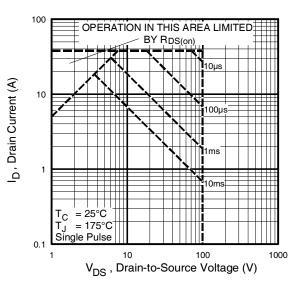
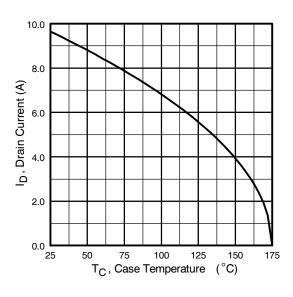


Fig 8. Maximum Safe Operating Area

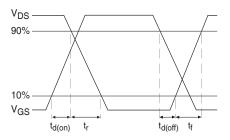
## International TOR Rectifier

## IRF520NPbF



 $V_{DS} \longrightarrow V_{DS}$   $V_{GS} \longrightarrow D.U.T.$   $V_{DD} \longrightarrow V_{DD}$   $V_{DU} \longrightarrow V_{DD}$   $V_{DU} \longrightarrow V_{DD}$   $V_{DU} \longrightarrow V_{DD}$   $V_{DU} \longrightarrow V_{DD}$   $V_{DD} \longrightarrow V$ 

Fig 10a. Switching Time Test Circuit



**Fig 9.** Maximum Drain Current Vs. Case Temperature

Fig 10b. Switching Time Waveforms

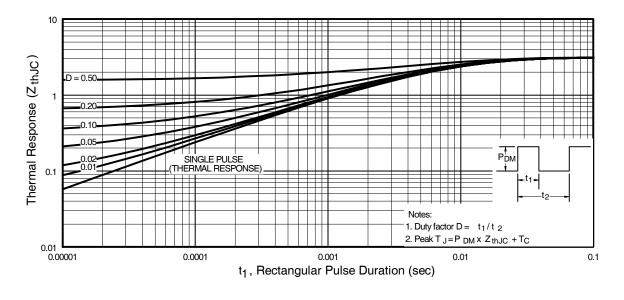


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

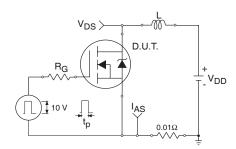


Fig 12a. Unclamped Inductive Test Circuit

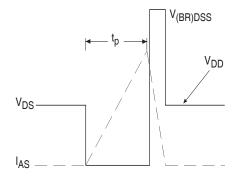


Fig 12b. Unclamped Inductive Waveforms

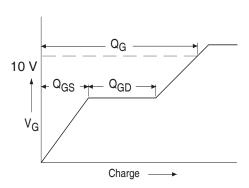


Fig 13a. Basic Gate Charge Waveform

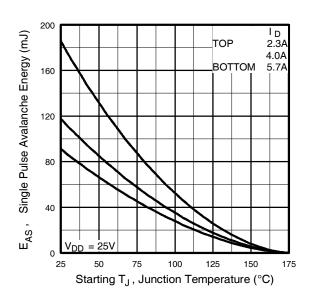


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

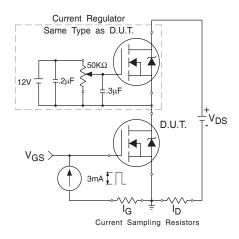
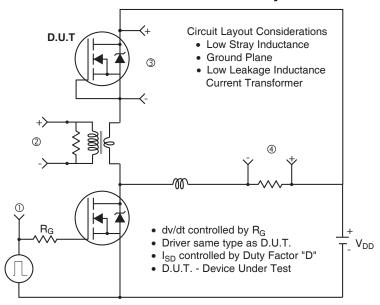


Fig 13b. Gate Charge Test Circuit

## Peak Diode Recovery dv/dt Test Circuit



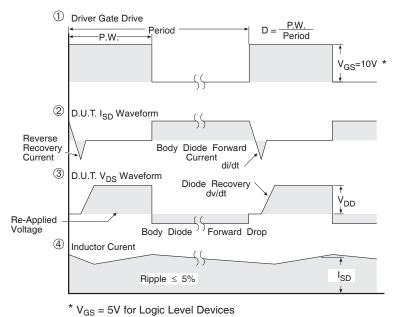
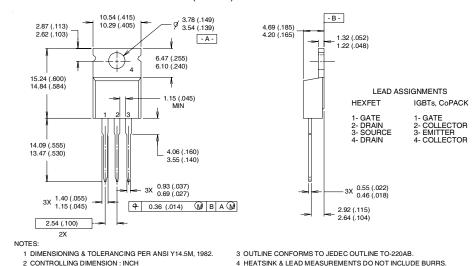


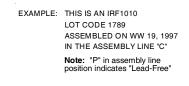
Fig 14. For N-Channel HEXFETS

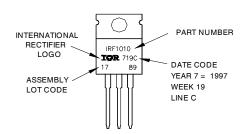
#### TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



## TO-220AB Part Marking Information





Data and specifications subject to change without notice.



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Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

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